



**12500 TI Boulevard, MS 8640, Dallas, Texas 75243**

**PCN# 20150821001**

**Qualification of FFAB as an additional Wafer Fab site option for select devices in the  
BICMOS13 process  
Change Notification / Sample Request**

**Date:** 8/24/2015  
**To:** MOUSER PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager ([PCN\\_ww\\_admin\\_team@list.ti.com](mailto:PCN_ww_admin_team@list.ti.com)).

PCN Team  
SC Business Services




**20150821001**  
**Attachment: 1**

**Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

<b>DEVICE</b>	<b>CUSTOMER PART NUMBER</b>
DS100BR210SQE/NOPB	null
DS100KR800SQE/NOPB	null
DS125BR401SQE/NOPB	null
DS125BR820NJYT	null
DS125DF111SQE	null
DS80PCI402SQE/NOPB	null
DS80PCI800SQE/NOPB	null
DS80PCI810NJYT	null
LMX2581SQE/NOPB	null

Technical details of this Product Change follow on the next page(s).

<b>PCN Number:</b>	20150821001		<b>PCN Date:</b>	08/24/2015				
<b>Title:</b>	Qualification of FFAB as an additional Wafer Fab site option for select devices in BICMOS13 Technology							
<b>Customer Contact:</b>	PCN Manager		<b>Dept:</b>	Quality Services				
<b>Proposed 1<sup>st</sup> Ship Date:</b>	11/24/2015	<b>Estimated Sample Availability:</b>	Date provided at sample request.					
<b>Change Type:</b>								
<input type="checkbox"/> Assembly Site	<input type="checkbox"/> Assembly Process	<input type="checkbox"/> Assembly Materials						
<input type="checkbox"/> Design	<input type="checkbox"/> Electrical Specification	<input type="checkbox"/> Mechanical Specification						
<input type="checkbox"/> Test Site	<input type="checkbox"/> Packing/Shipping/Labeling	<input type="checkbox"/> Test Process						
<input type="checkbox"/> Wafer Bump Site	<input type="checkbox"/> Wafer Bump Material	<input type="checkbox"/> Wafer Bump Process						
<input checked="" type="checkbox"/> Wafer Fab Site	<input type="checkbox"/> Wafer Fab Materials	<input type="checkbox"/> Wafer Fab Process						
	<input type="checkbox"/> Part number change							
<b>PCN Details</b>								
<b>Description of Change:</b>								
This change notification is to announce the addition of FFAB as an additional Wafer Fab site option for the products listed in the product affected section of this document.								
<b>Current Wafer Fab Site</b>		<b>Process</b>	<b>Wafer Diameter</b>					
MAINEFAB		BICMOS13	200mm					
<b>Additional Wafer Fab Site</b>		<b>Process</b>	<b>Wafer Diameter</b>					
FFAB		BICMOS13	200mm					
<b>Reason for Change:</b>								
Continuity of Supply								
<b>Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):</b>								
None								
<b>Changes to product identification resulting from this PCN:</b>								
<b>Current</b>								
Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City					
MAINEFAB	CUA	USA	South Portland					
<b>New</b>								
Chip Site	Chip Site Origin (20L)	Chip Site Country Code (21L)	Chip Site City					
FR-BIP-1	TID	DEU	Freising					
Sample product shipping label (not actual product label)								
<div style="display: flex; justify-content: space-between; align-items: flex-start;"> <div style="width: 30%;">  <p>MADE IN: Malaysia 2DC: 20:</p> <table border="1" style="font-size: small;"> <tr> <td>MSL '2 / 260C / 1 YEAR</td> <td>SEAL DT</td> </tr> <tr> <td>MSL 1 / 235C / UNLIM</td> <td>03/29/04</td> </tr> </table> <p>OPT: 39 ITEM: 39 <b>LBL: 5A (L)T0:1750</b></p> </div> <div style="width: 15%; text-align: center;">  </div> <div style="width: 20%; text-align: center;">  </div> <div style="width: 35%;"> <p>(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483SI2 (P) (2P) REV: (V) 0033317 (20L) CS0: SHE (21L) CC0: USA (22L) AS0: MLA (23L) AG0: MYS</p> </div> </div>					MSL '2 / 260C / 1 YEAR	SEAL DT	MSL 1 / 235C / UNLIM	03/29/04
MSL '2 / 260C / 1 YEAR	SEAL DT							
MSL 1 / 235C / UNLIM	03/29/04							

**Product Affected:**

DS100BR210SQ/NOPB	DS110DX410SQ/NOPB	DS125BR820NJYR	DS80PCI800SQ/NOPB
DS100BR210SQE/NOPB	DS110DX410SQE/NOPB	DS125BR820NJYT	DS80PCI800SQE/NOPB
DS100DX410SQ/NOPB	DS125BR210SQ/NOPB	DS125DF111SQ	DS80PCI810NJYR
DS100DX410SQE/NOPB	DS125BR210SQE/NOPB	DS125DF111SQE	DS80PCI810NJYT
DS100KR401SQ/NOPB	DS125BR401SQ/NOPB	DS125DF410SQ/NOPB	LM97937RMER
DS100KR401SQE/NOPB	DS125BR401SQE/NOPB	DS125DF410SQE/NOPB	LM97937RMET
DS100KR800SQ/NOPB	DS125BR800SQ/NOPB	DS125RT410SQ/NOPB	LMX2581SQ/NOPB
DS100KR800SQE/NOPB	DS125BR800SQE/NOPB	DS125RT410SQE/NOPB	LMX2581SQE/NOPB
DS110DF111SQ/NOPB	DS125BR810NJYR	DS80PCI402SQ/NOPB	LMX2581SQX/NOPB
DS110DF111SQE/NOPB	DS125BR810NJYT	DS80PCI402SQE/NOPB	

**Qualification Report****BiCMOS13 Process (LMX2581B) Release at FFAB**

Approve Date 31-Jul-2015

**Product Attributes**

Die Attributes	Qual Device: LMX2581SQENOPB
Wafer Fab Supplier	FFAB
Wafer Fab Process	BC13
Wafer Diameter	200mm

- QBS: Qual by Similarity

- Qual Device LMX2581SQENOPB is qualified at LEVEL3-260CG

**Qualification Results**

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: LMX2581SQENOPB
ELFR	Early Life Failure Rate, Tj=160C	48 Hours	3/2400/0
HTOL	Life Test, Tj=160C	500 Hours	3/231/0
AC	Autoclave 121C	96 Hours	3/231/0
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0
TC	Temperature Cycle, -40/125C	1000 Cycles	3/231/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	3/231/0
HBM	ESD - HBM	2000 V	3/9/0
CDM	ESD - CDM	750 V	3/9/0
LU	Latch-up	(per JESD78)	3/18/0
ED	Electrical Characterization	Per datasheet parameters	Pass

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: <http://www.ti.com/>

Green/Pb-free Status:

Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	<a href="mailto:PCNAmericasContact@list.ti.com">PCNAmericasContact@list.ti.com</a>
Europe	<a href="mailto:PCNEuropeContact@list.ti.com">PCNEuropeContact@list.ti.com</a>
Asia Pacific	<a href="mailto:PCNAsiaContact@list.ti.com">PCNAsiaContact@list.ti.com</a>
Japan	<a href="mailto:PCNJapanContact@list.ti.com">PCNJapanContact@list.ti.com</a>